

## Selective Control of Test-Access Ports in Integrated Circuits

### Abstract of the Disclosure

To facilitate testing, some integrated circuits include built-in test  
5 circuits, called test-access ports (TAPs). The present inventor recognized that  
TAPs are sometimes used with automatic testers that have limitations, such as  
insufficient memory capacity, that make it difficult or costly to test some  
integrated circuits, such as microprocessors. Accordingly, this disclosure  
teaches, among other things, inputting test signals to a TAP of an integrated  
10 circuit using a first device, such as an automatic tester, and outputting state  
data related to the input test signals from the TAP using a second device.

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